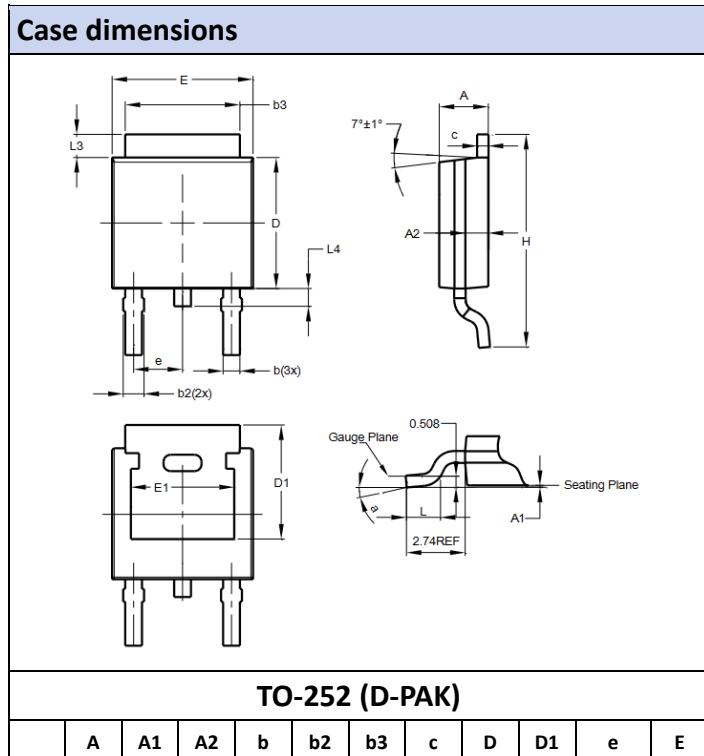


## N-Channel MOSFET

Primary characteristics			
Symbol	Parameter	Value	Unit
$I_D$	Continuous drain current (@ $T_C=25^\circ\text{C}$ )	8	A
$V_{DS}$	Drain source voltage	650	V
$R_{DSON-}\text{typ}(@V_{GS}=10\text{V})$	Static drain-source on-resistance	<1.3 Typ. 0.95	$\Omega$



TO-252 (D-PAK)												
	A	A1	A2	b	b2	b3	c	D	D1	e	E	
<b>TYP</b>	2.29	0.08	1.07	0.783	0.95	5.33	0.531	6.1	-	2.286	6.58	
MIN	2.19	0	0.97	0.64	0.76	5.21	0.45	6.0	5.21	BSC	6.45	
MAX	2.39	0.13	1.17	0.88	1.14	5.5	0.58	6.2	-		6.7	
	E1	H	L	L3	L4	a	All measurements in mm					
<b>TYP</b>	9.91	9.91	1.59	1.08	0.83	-						
MIN	9.40	9.4	1.4	0.88	0.64	0°						
MAX	10.41	10.41	1.78	1.27	1.02	10°						

Maximum and thermal ratings ( $T_C = 25^\circ\text{C}$ unless otherwise specified)											
Characteristics			Symbol	Value						Unit	
Drain-source voltage <sup>1)</sup>			$V_{DSS}$	650						V	
Gate-source voltage			$V_{GSS}$	$\pm 30$						V	
Continuous drain current @ $T_C=25^\circ\text{C}$			$I_D$	8						A	
Continuous drain current @ $T_C=100^\circ\text{C}$			$I_D$	<a href="#">See: Max. drain current vs case temperature</a>						A	
Pulsed drain current @ $V_{GS}=10\text{V}$ <sup>2)</sup>			$I_{DM}$	<a href="#">See: Maximum peak current capability</a>						A	
Single pulse avalanche energy			$E_{AS}$	450						mJ	
Peak diode recovery $dv/dt$ <sup>3)</sup>			$dv/dt$	5.0						V/ns	
Power Dissipation @ $T_C=25^\circ\text{C}$			$P_D$	120						W	
Derating factor above 25°C				0.96						W/ $^\circ\text{C}$	
Operating junction temperature range			$T_J, T_{STG}$	-55 ~ 150						$^\circ\text{C}$	
Maximum temperature for soldering Leads at 0.063in (1.6mm) from case for 10s, package body for 10s			$T_L$ $T_{PAK}$	300 260						$^\circ\text{C}$	
Thermal resistance junction-ambient			$R_{eJA}$	75						$^\circ\text{C}/\text{W}$	
Thermal resistance junction-case			$R_{eJC}$	1.04						$^\circ\text{C}/\text{W}$	

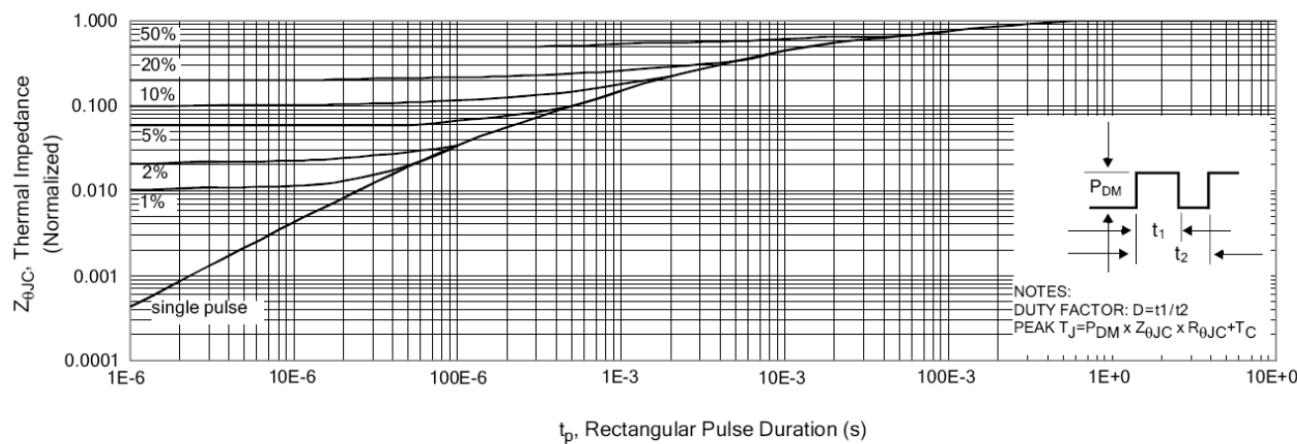
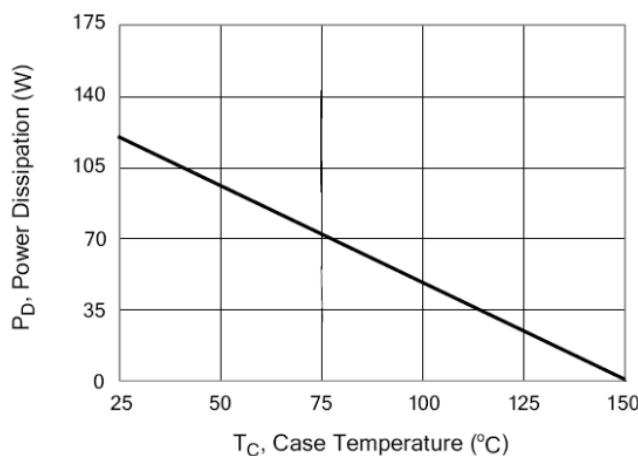
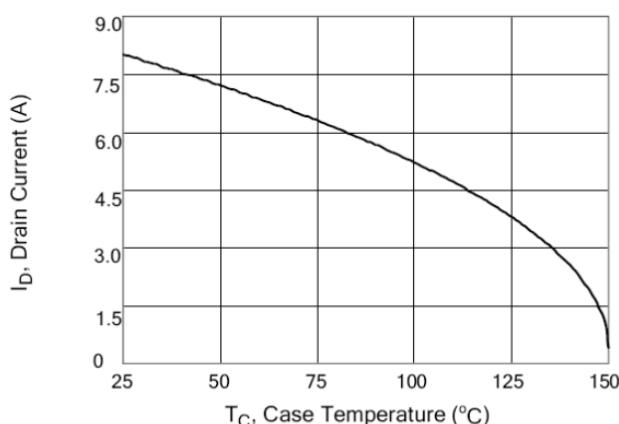
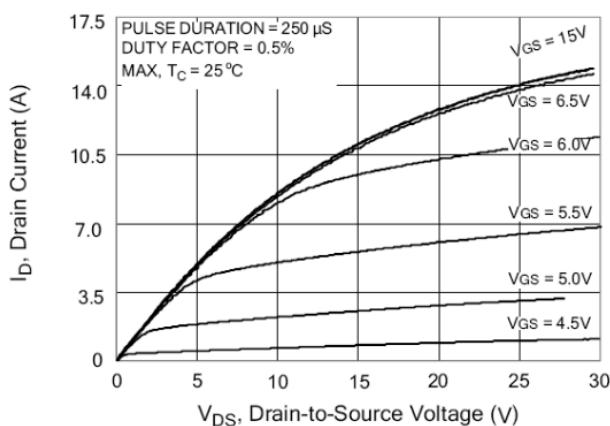
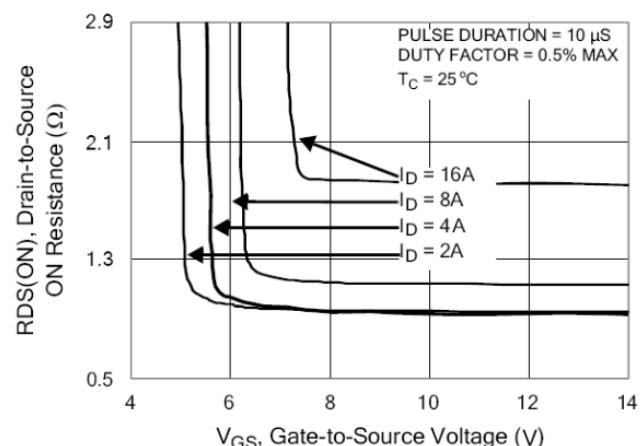
Electrical characteristics ( $T_c = 25^\circ\text{C}$ unless otherwise specified)						
Characteristics	Test condition	Symbol	Min.	Value Typ.	Max.	Unit
<b>OFF characteristics</b>						
Drain-to-source breakdown voltage	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	$BV_{DSS}$	650	-	-	V
Drain-to-source leakage current	$V_{DS}=650\text{V}, V_{GS}=0\text{V}$	$I_{DSS}$	-	-	1	$\mu\text{A}$
	$V_{DS}=520\text{V}, V_{GS}=0\text{V}, T_J=125^\circ\text{C}$		-	-	100	
Gate-to-source leakage current	$V_{GS}=+30\text{V}, V_{DS}=0\text{V}$	$I_{GSS}$	-	-	100	$\text{nA}$
	$V_{GS}=-30\text{V}, V_{DS}=0\text{V}$		-	-	-100	
<b>ON characteristics</b>						
Static drain-to-source on-resistance <sup>4)</sup>	$V_{GS}=10\text{V}, I_D=4.0\text{A}$	$R_{DS(\text{ON})}$	-	0.95	1.3	$\Omega$
Gate threshold voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	$V_{GS(\text{TH})}$	2.0	-	4.0	V
Forward transconductance <sup>4)</sup>	$V_{DS}=20\text{V}, I_D=8.0\text{A}$	$g_{fs}$	-	10	-	S
<b>Dynamic characteristics</b>						
Input capacitance	$V_{GS}=0\text{V}, V_{DS}=25\text{V}, f=1.0\text{MHz}$	$C_{iss}$	-	1240	-	$\text{pF}$
Reverse transfer capacitance		$C_{rss}$	-	14	-	
Output capacitance		$C_{oss}$	-	110	-	
Total gate charge	$V_{DD}=325\text{V}, I_D=8.0\text{A}, V_{GS}=0 \text{ to } 10\text{V}$	$Q_g$	-	28	-	$\text{nC}$
Gate-to-source charge		$Q_{gs}$	-	5.6	-	
Gate-to-drain (Miller) charge		$Q_{gd}$	-	11.2	-	
<b>Resistive switching characteristics</b>						
Turn-on delay time	$V_{DD}=325\text{V}, I_D=8.0\text{A}, V_{GS}=10\text{V}, R_G=9.1\Omega$	$t_{d(\text{ON})}$	-	13	-	$\text{ns}$
Rise time		$t_{rise}$	-	15	-	
Turn-off delay time		$t_{d(\text{OFF})}$	-	40	-	
Fall time		$t_{fall}$	-	22	-	
<b>Source-drain body diode characteristics</b>						
Continuous source current <sup>4)</sup>	Integral PN-diode in MOSFET	$I_{SD}$	-	-	8	$\text{A}$
Pulsed source current <sup>4)</sup>		$I_{SM}$	-	-	32	
Diode forward voltage	$I_S=8.0\text{A}, V_{GS}=0\text{V}$	$V_{SD}$	-	-	1.5	V
Reverse recovery time	$V_{GS}=0\text{V}, I_F=8.0\text{A}, d_I/dt=100\text{A}/\mu\text{s}$	$t_{rr}$	-	555	-	ns
Reverse recovery charge		$Q_{rr}$	-	3.4	-	$\mu\text{C}$

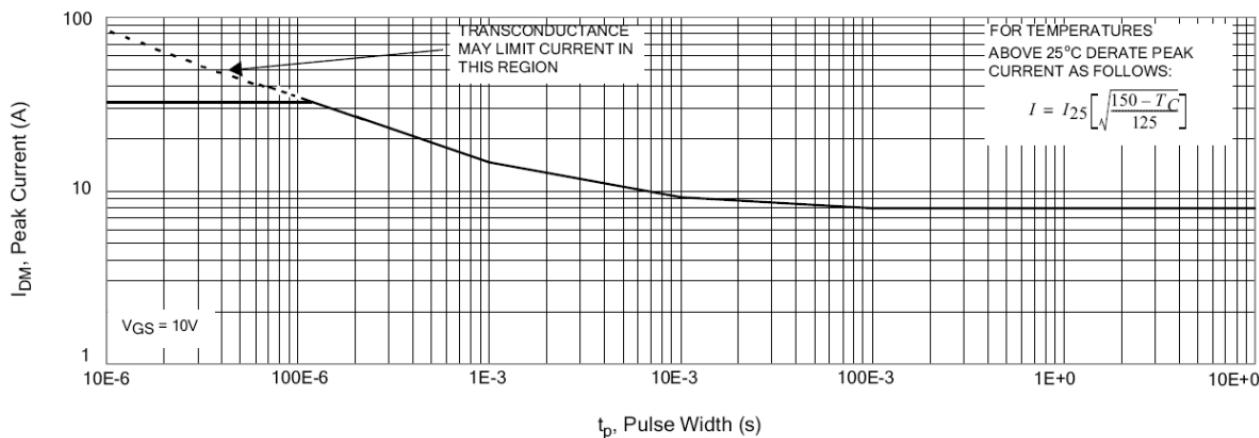
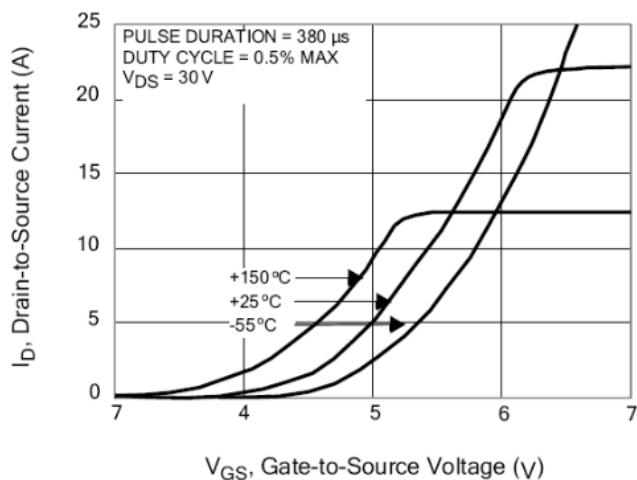
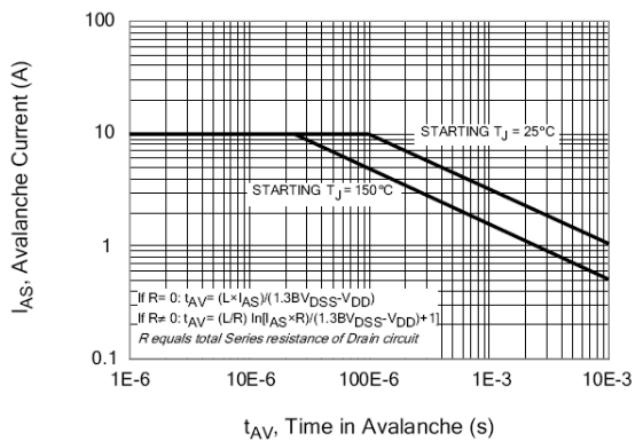
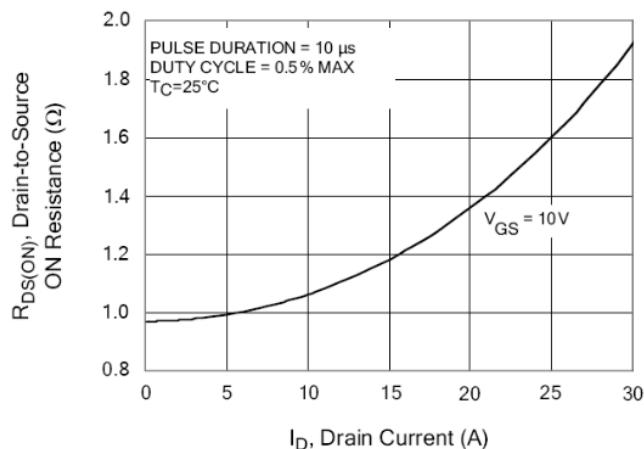
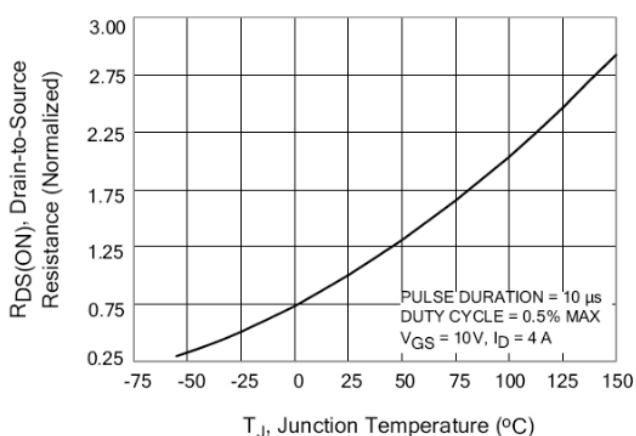
1)  $T_J: 25^\circ\text{C} \sim 150^\circ\text{C}$

2) Repetitive rating; pulse width limited by maximum junction temperature

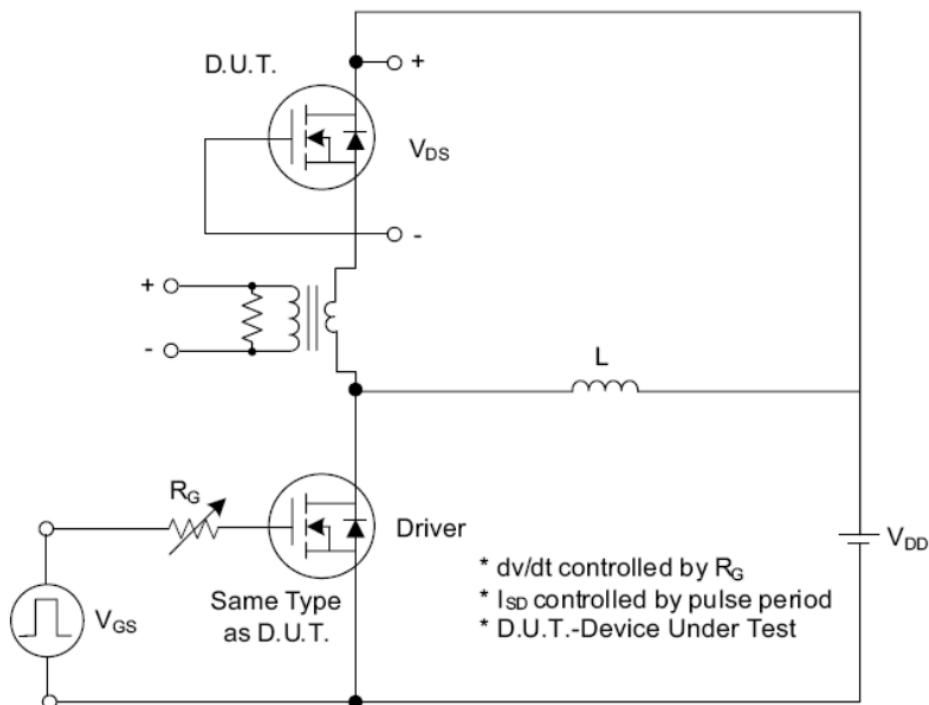
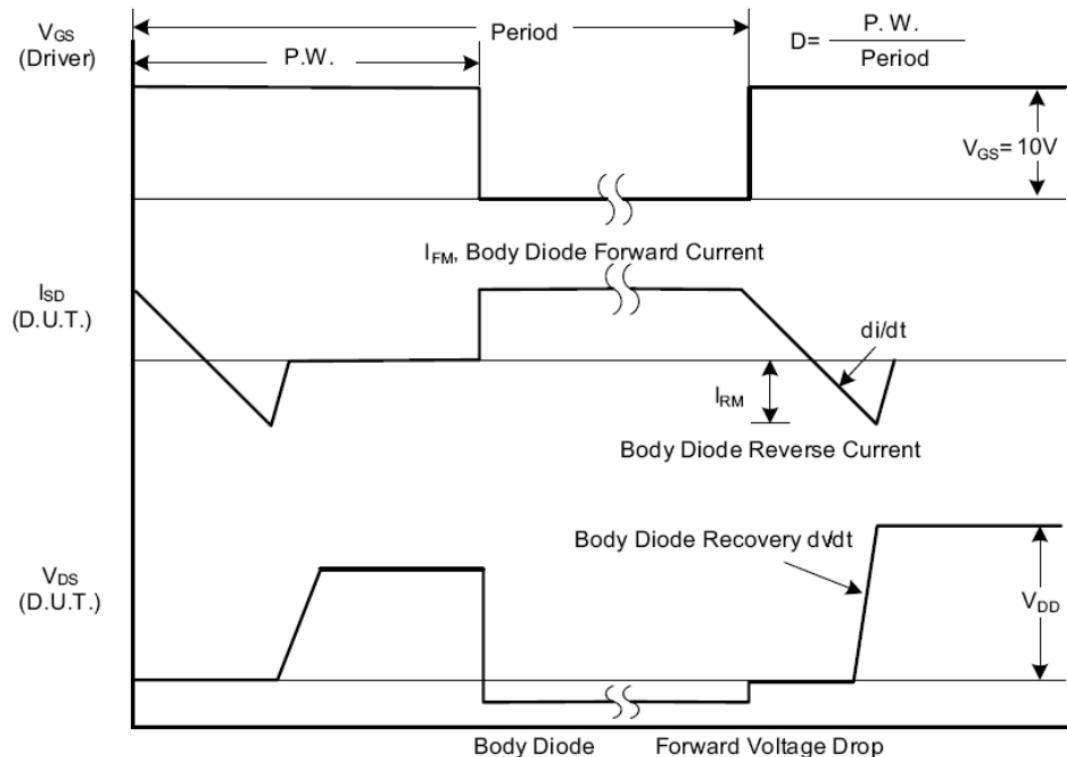
3)  $I_{sd}=20\text{A} \text{ di/dt} < 100 \text{ A}/\mu\text{s}, V_{DD} < BV_{DSS}, T_J=150^\circ\text{C}$

4) Pulse width  $\leq 380\mu\text{s}$ ; duty cycle  $\leq 2\%$

**Maximum effective thermal impedance, junction-to-case**

**Maximum power dissipation  
vs case temperature**

**Maximum continuous drain current  
vs case temperature**

**Typical output characteristics**

**Typical drain-to-source ON resistance  
vs gate voltage and drain current**


**Maximum peak current capability**

**Typical transfer characteristics**

**Unclamped inductive switching capability**

**Typical drain-to-source ON resistance vs drain current**

**Typical drain-to-source ON resistance vs junction temperature**


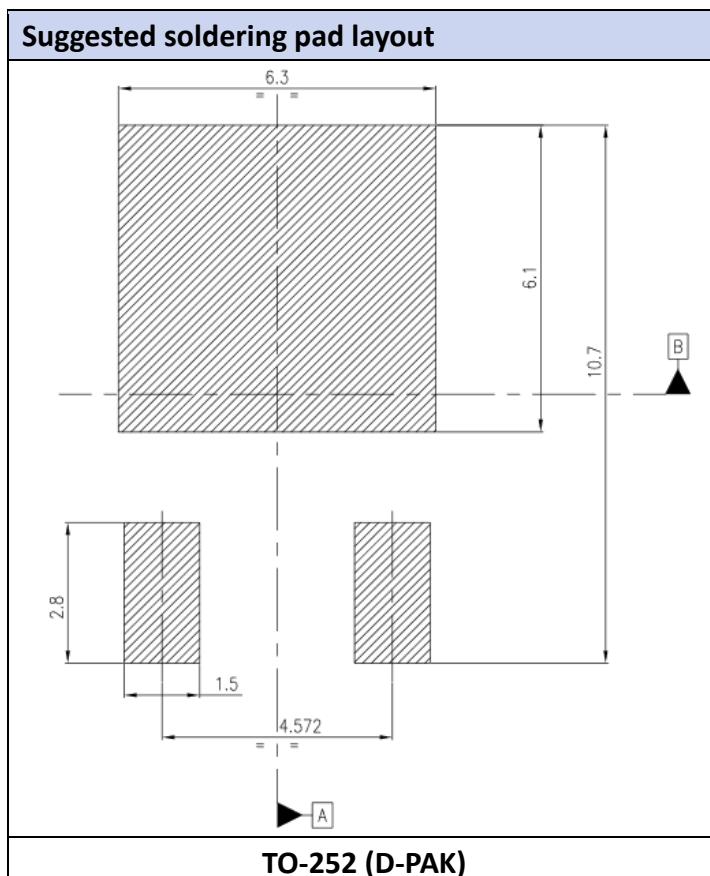
Typical breakdown voltage vs junction temperature	Typical threshold voltage vs junction temperature
<p><b>Typical breakdown voltage vs junction temperature</b></p> <p><math>V_{GS} = 0V</math> <math>I_D = 250 \mu A</math></p>	<p><b>Typical threshold voltage vs junction temperature</b></p> <p><math>V_{GS} = V_{DS}</math> <math>I_D = 250 \mu A</math></p>
Maximum forward bias safe operating area	Typical capacitance vs drain-to-source voltage
<p><b>Maximum forward bias safe operating area</b></p> <p><math>T_J = \text{MAX RATED}</math> <math>T_C = 25^\circ C</math></p> <p><math>\text{Single Pulse}</math></p> <p><math>10\mu s</math> <math>100\mu s</math> <math>1ms</math> <math>10ms</math></p> <p><math>DC</math></p> <p><math>T_J = \text{MAX RATED}</math> <math>T_C = 25^\circ C</math></p>	<p><b>Typical capacitance vs drain-to-source voltage</b></p> <p><math>V_{GS} = 0V, f = 1MHz</math></p> <p><math>C_{iss} = C_{gs} + C_{gd}</math> <math>C_{oss} \approx C_{ds} + C_{gd}</math> <math>C_{rss} = C_{gd}</math></p>
Typical gate charge vs gate-to-source voltage	Typical body diode transfer characteristics
<p><b>Typical gate charge vs gate-to-source voltage</b></p> <p><math>V_{DS} = 165V</math> <math>V_{DS} = 325V</math> <math>V_{DS} = 480V</math></p> <p><math>I_D = 8A</math></p>	<p><b>Typical body diode transfer characteristics</b></p> <p><math>+150^\circ C</math> <math>+25^\circ C</math></p> <p><math>V_{GS} = 0V</math></p>

**Peak diode recovery dv/dt test circuit**

**Peak diode recovery dv/dt waveforms**


Switching test circuit	Switching waveforms
Gate charge test circuit	Gate charge waveform
Unclamped inductive switching test circuit	Unclamped inductive switching waveforms

**Ordering information**

Part Number	Package	Shipping Quantity	Dimensions
AKS08N65B	TO-252 (D-PAK)	2500 pcs / reel	---


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